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(12) **United States Design Patent** (10) **Patent No.:** **US D884,166 S**
Wang (45) **Date of Patent:** **** May 12, 2020**

(54) **LOW PROFILE PROBE HANDLE**
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(73) Assignee: **Avent, Inc.**, Alpharetta, GA (US)

(**) Term: **15 Years**

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(51) **LOC (12) Cl.** **24-02**

(52) **U.S. Cl.**
USPC **D24/133**

(58) **Field of Classification Search**
USPC D24/127, 128, 129, 130, 131, 133, 134, D24/137, 138, 140, 141, 142, 143, 200; 600/101, 104, 164; D8/20, 376, 363; 128/200.24, 207.14, 207.15; 604/264, 604/523-528, 272, 187, 158, 164.01, 604/164.11, 181, 184, 227; 606/181, 185
CPC A61B 17/320016; A61B 17/0057; A61B 17/00; A61B 18/14; A61M 25/00; A61M 25/0043; A61M 25/0067; A61M 39/00; A61M 27/00

See application file for complete search history.

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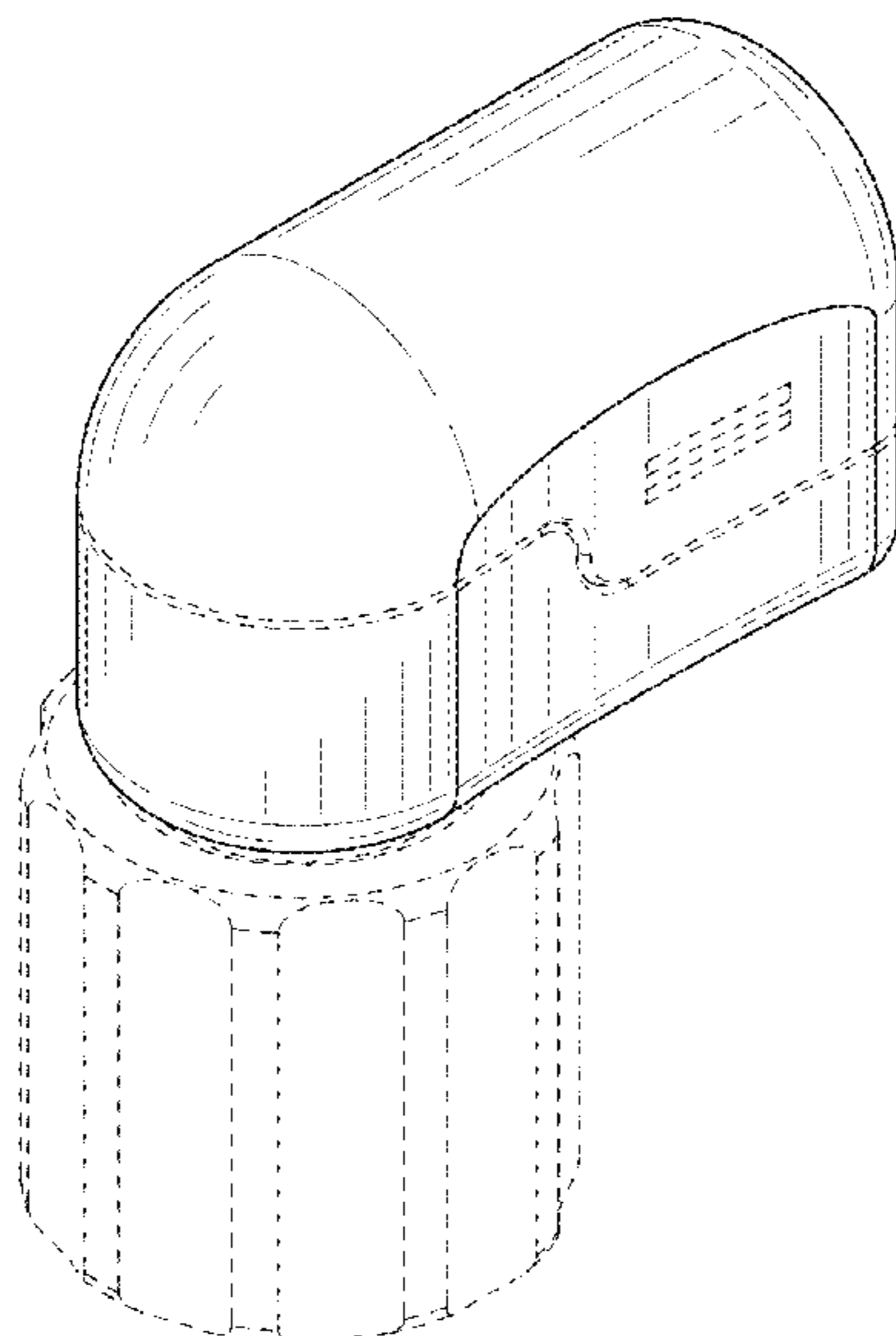
(57) **CLAIM**

The ornamental design for a low profile probe handle, as shown and described.

DESCRIPTION

FIG. 1 is a front perspective view of a low profile probe handle according to the present design;
FIG. 2 is a rear perspective view of the low profile probe handle of FIG. 1;
FIG. 3 is a front view of the low profile probe handle of FIG. 1;
FIG. 4 is a right side view of the low profile probe handle of FIG. 1;
FIG. 5 is a rear view of the low profile probe handle of FIG. 1;
FIG. 6 is a left side view of the low profile probe handle of FIG. 1;
FIG. 7 is a top view of the low profile probe handle of FIG. 1;
FIG. 8 is a bottom view of the low profile probe handle of FIG. 1; and,
FIG. 9 is a right side view of the low profile probe handle of FIG. 1, shown in an environment of use.
The broken lines shown in the drawings are for the purpose of illustrating environmental structure and portions of the low profile probe handle that form no part of the claimed design.

1 Claim, 5 Drawing Sheets



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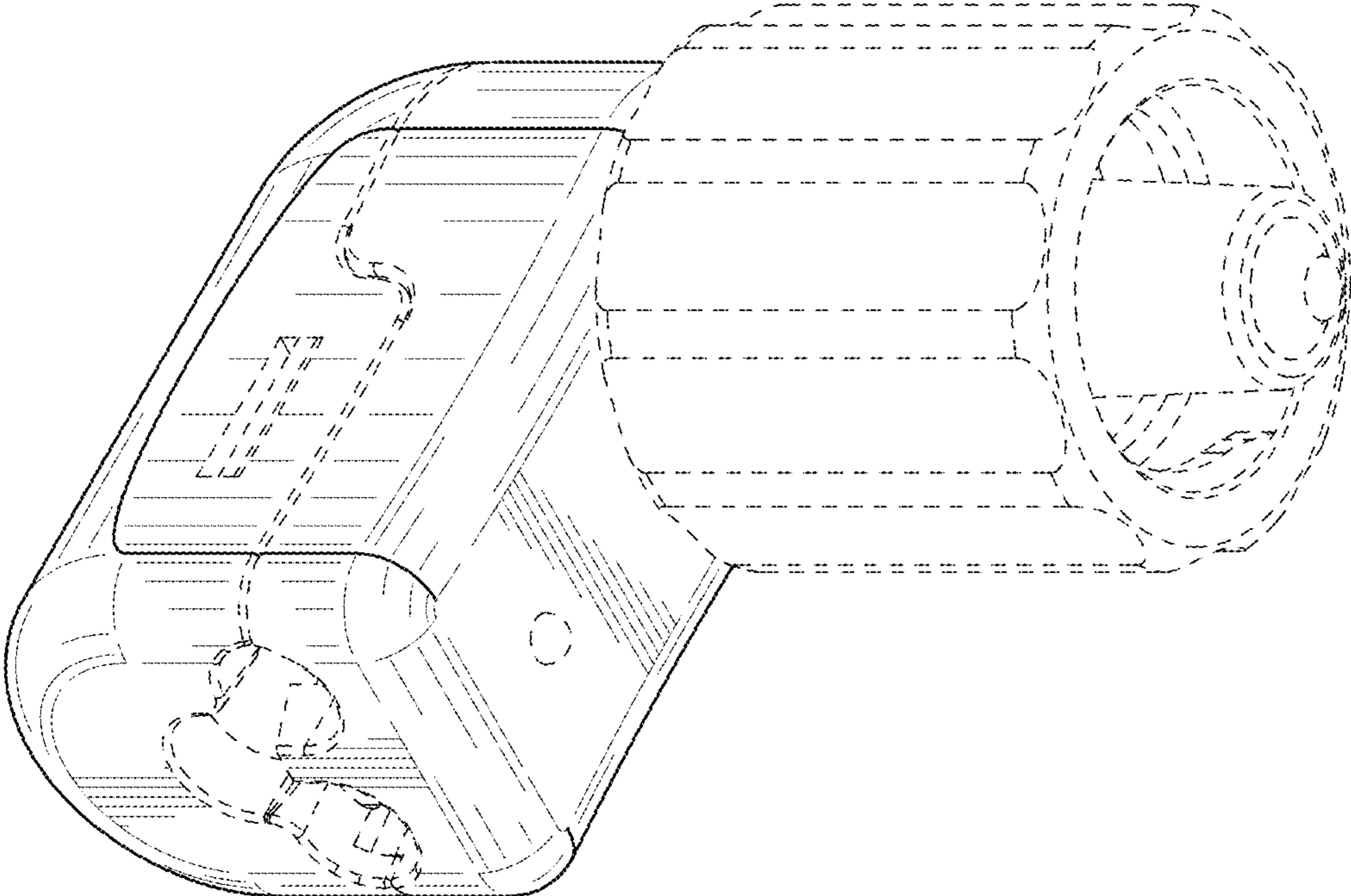


FIG. 1

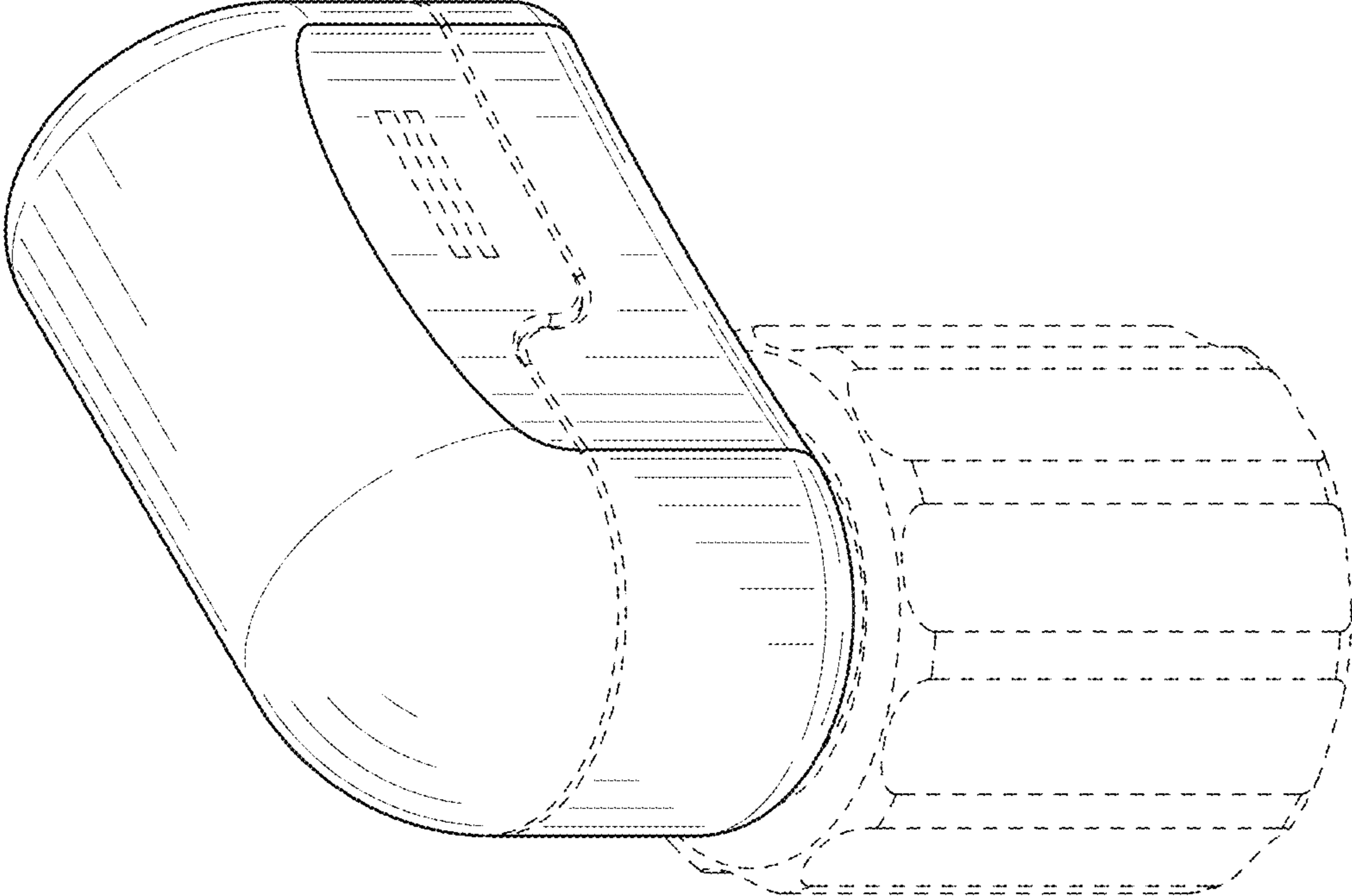


FIG. 2

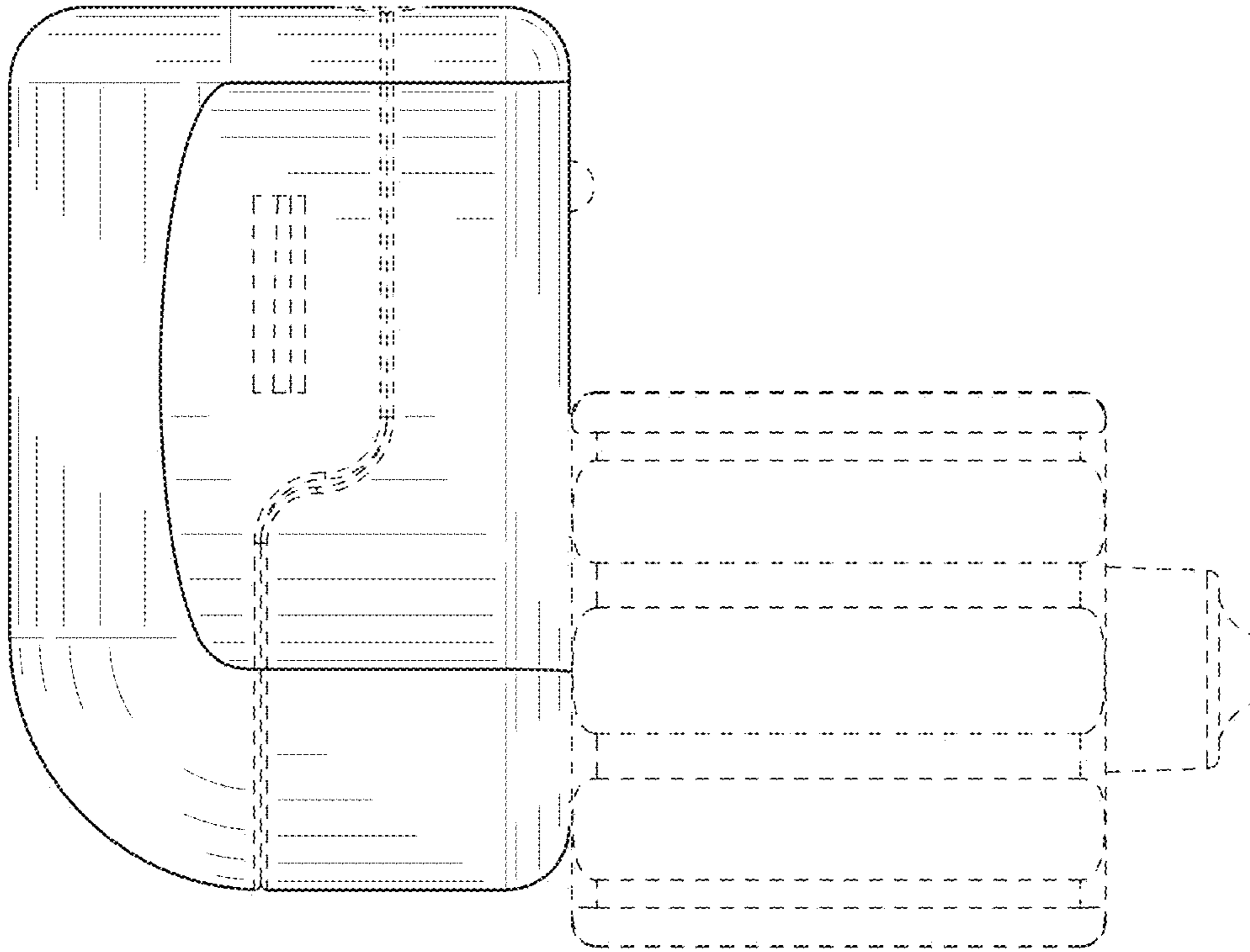


FIG. 4

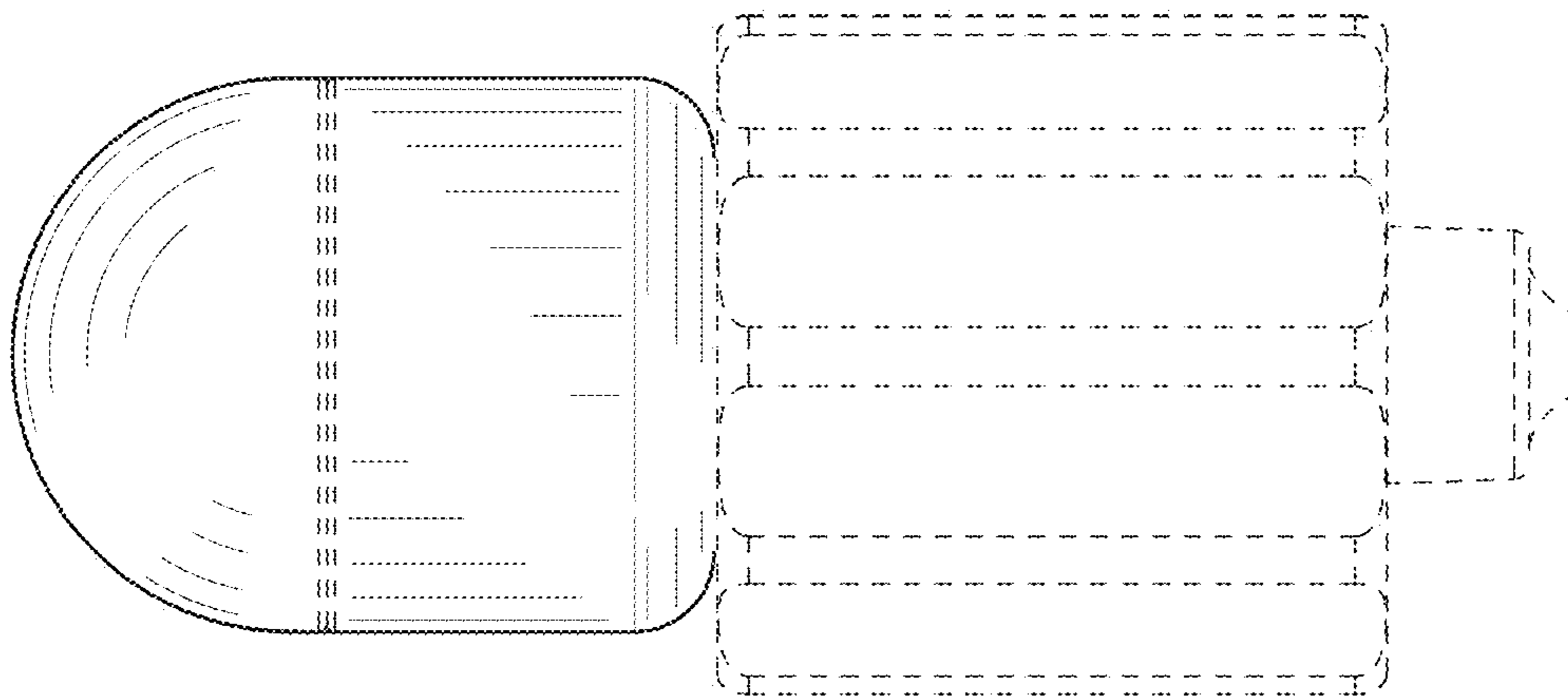


FIG. 3

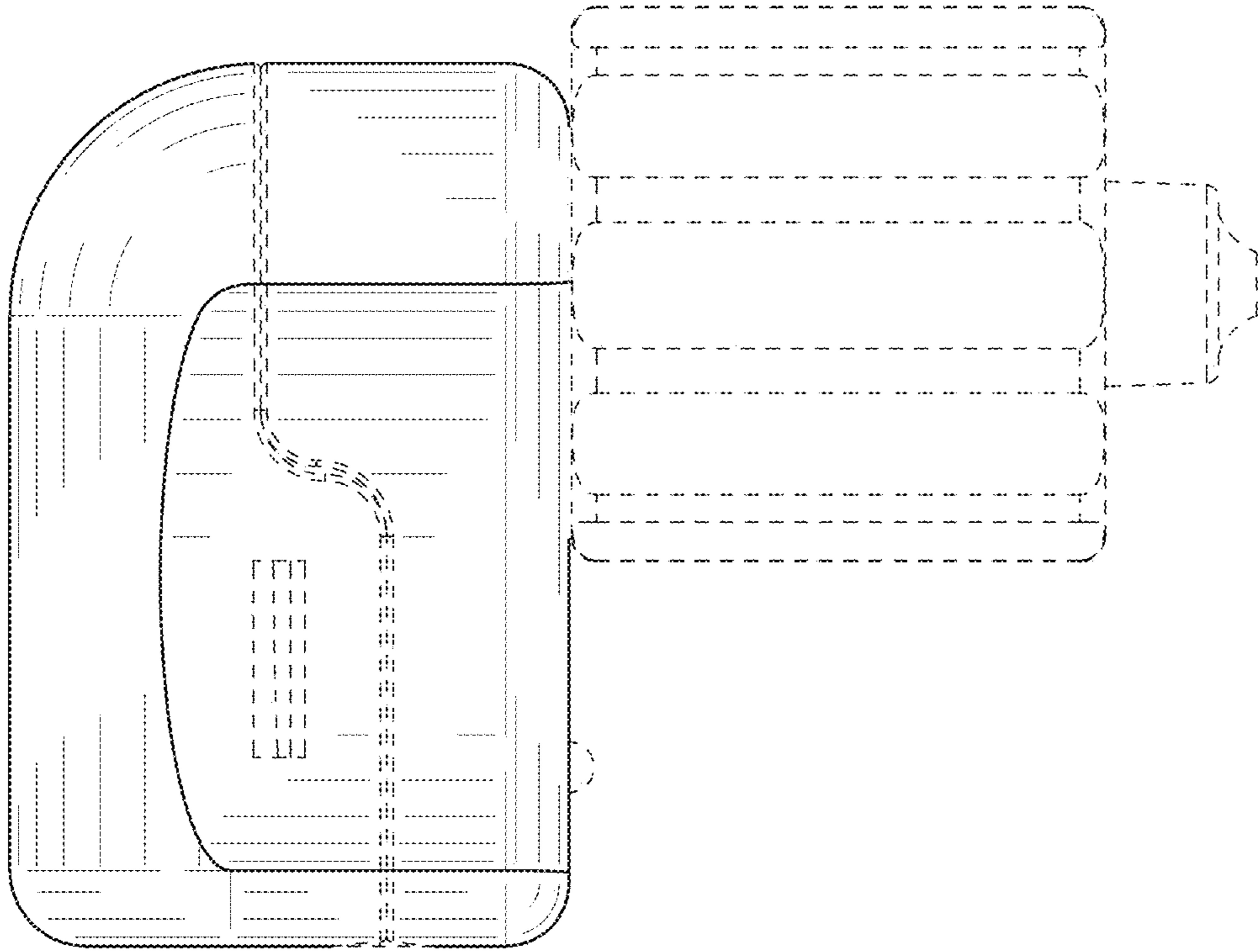


FIG. 5

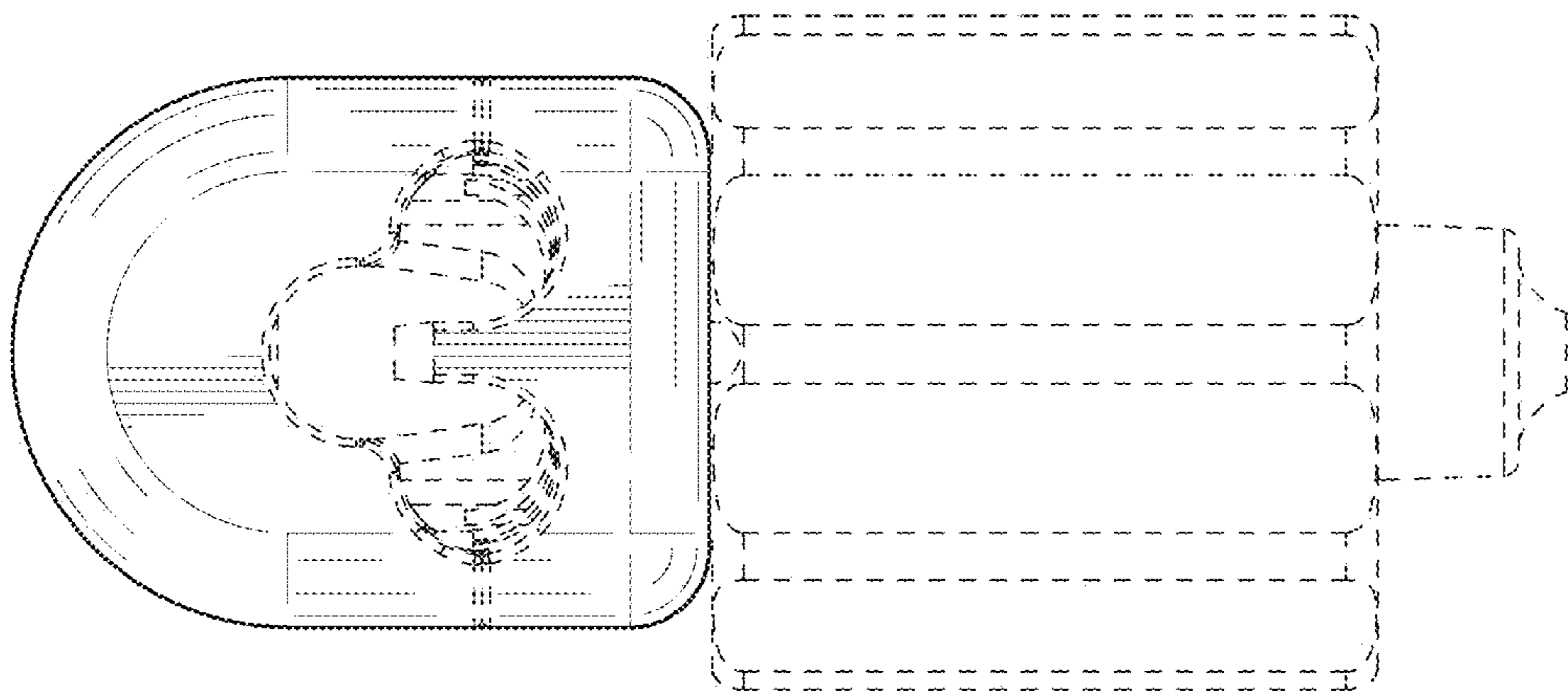


FIG. 6

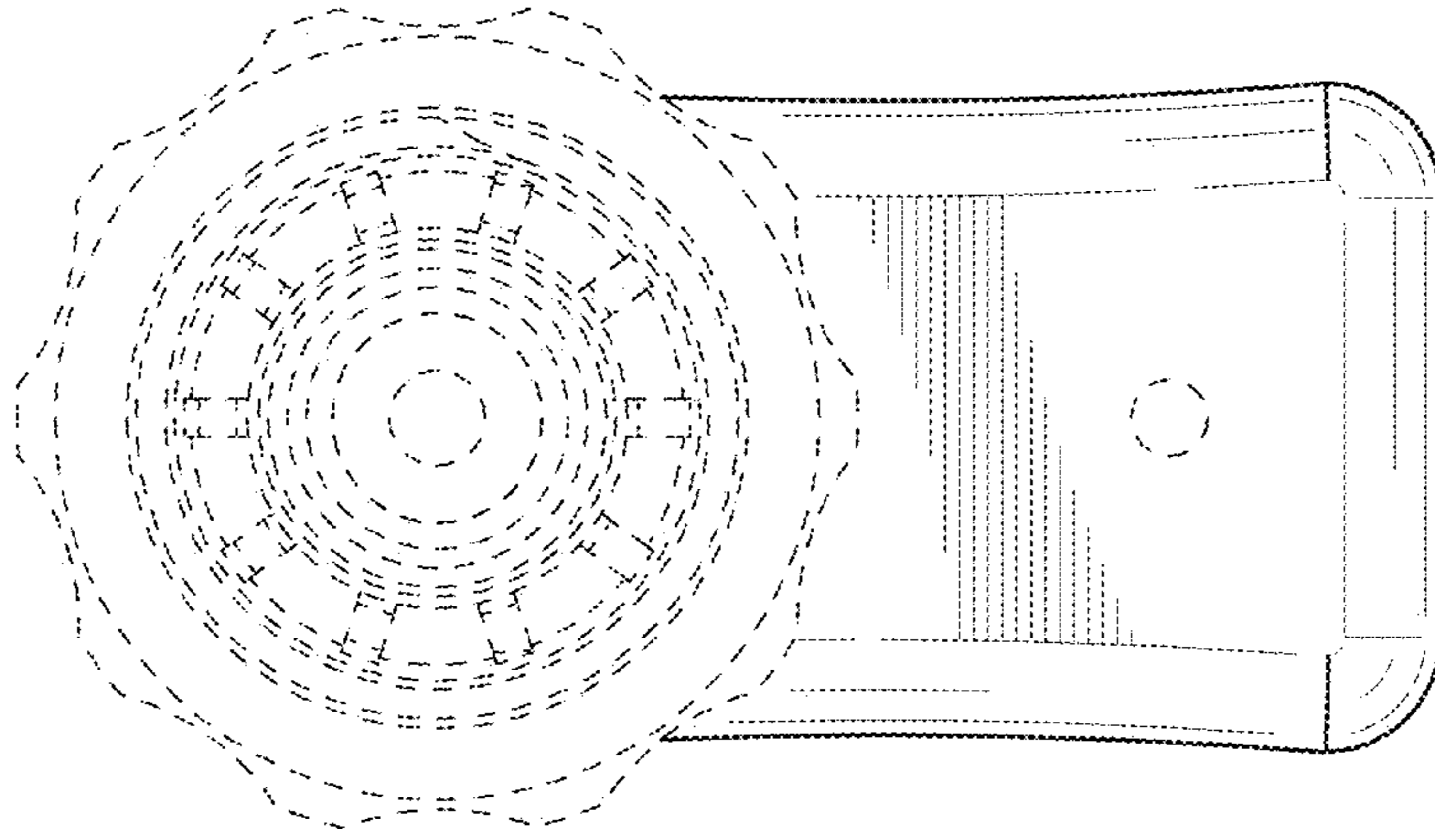


FIG. 7

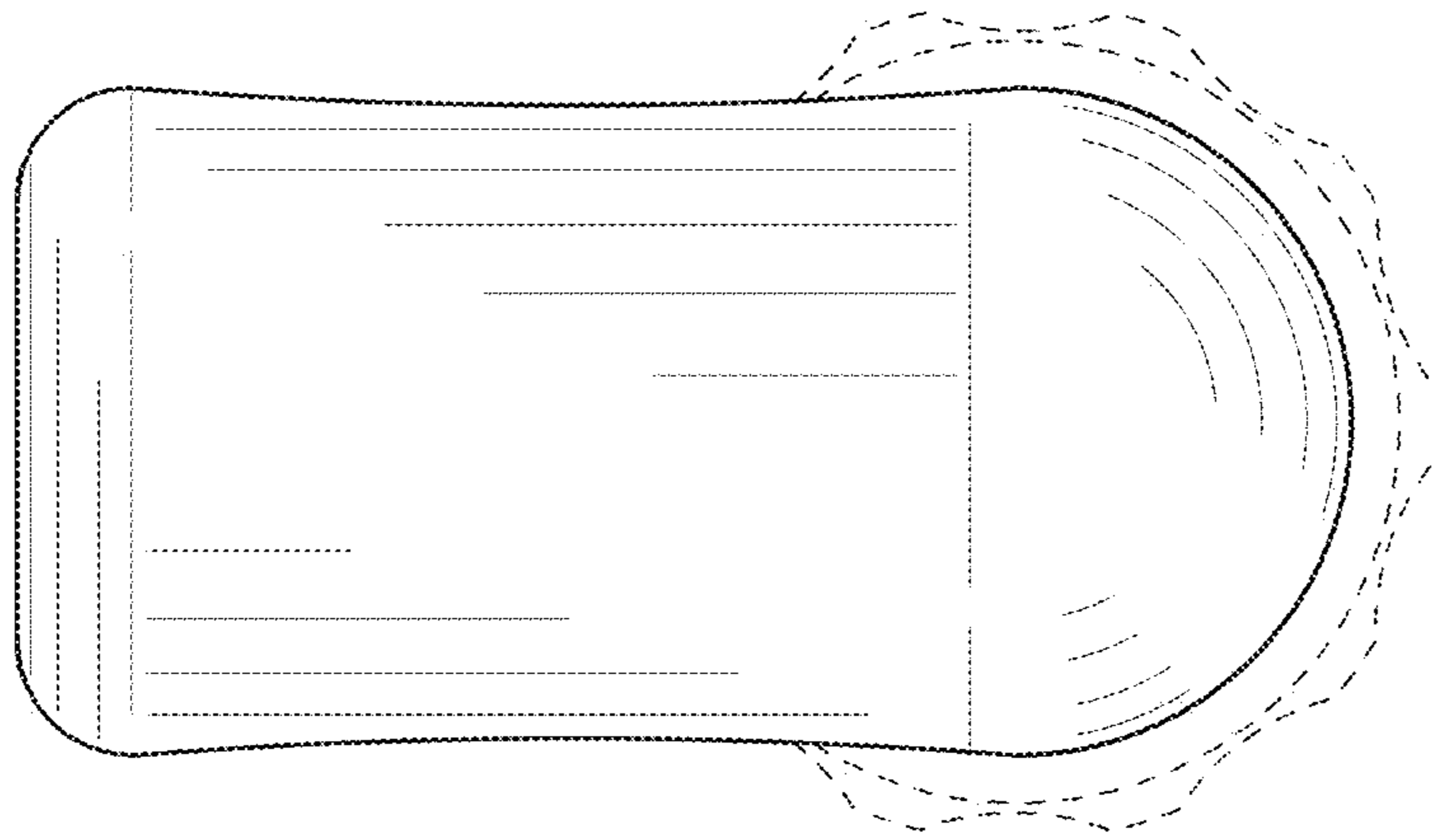


FIG. 8

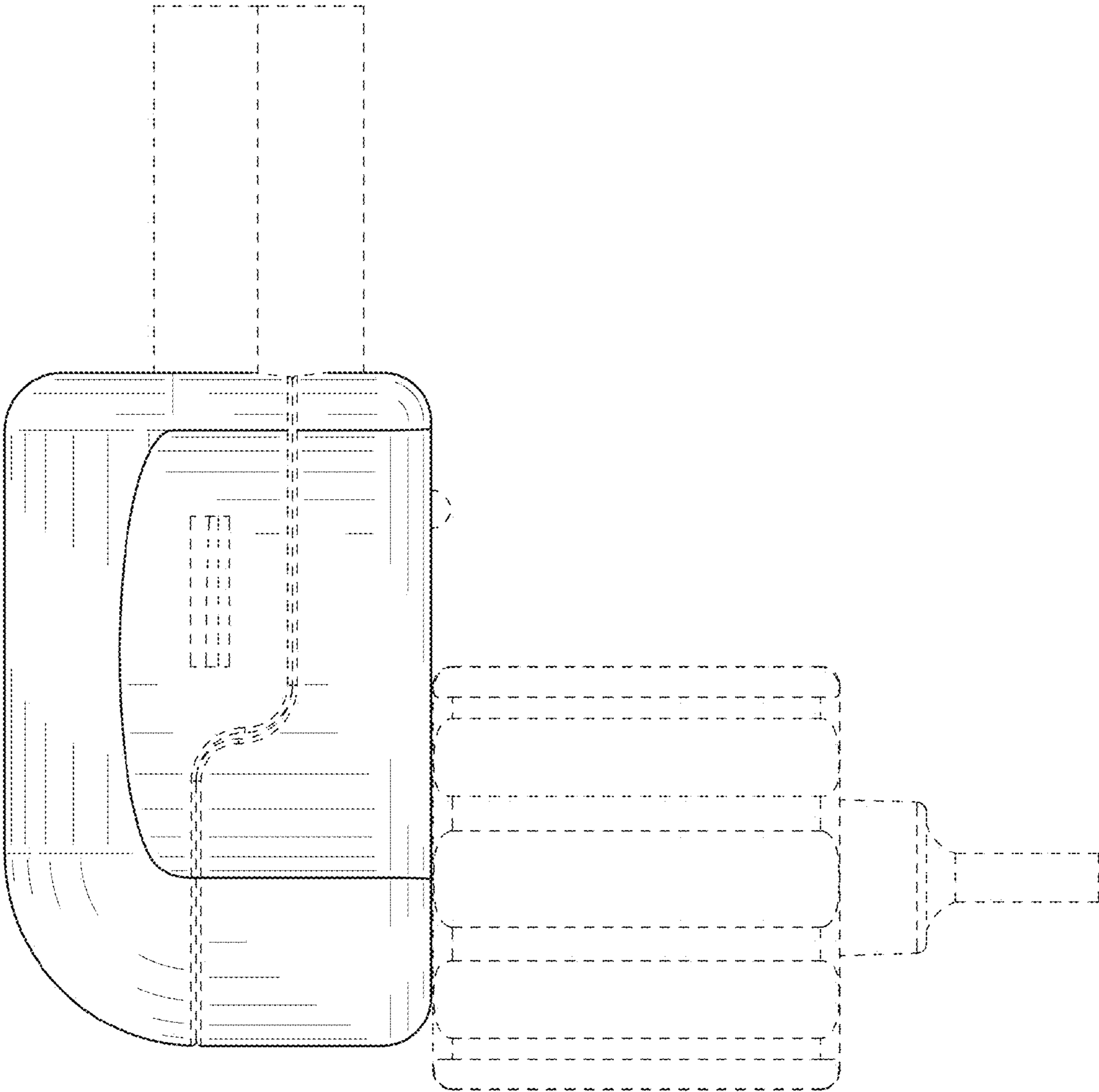


FIG. 9